

Multilayer BZO/YBCO Thick Films for High J_c in High Fields

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Abstract—A multilayer (ML) scheme was recently developed to facilitate diffusion of Ca from two thin ($\text{Ca}_{0.3}\text{Y}_{0.7}$)BCO layers sandwiched with three BZO/YBCO layers and the consequent dynamic Ca/Cu substitution on tensile strained YBCO lattice during the growth of c-axis aligned BaZrO_3 dimensional artificial pinning centers (BZO 1D-APCs) in BZO/YBCO nanocomposite films. The substitution of smaller Cu ions by larger Ca ones is found energetically preferable by inducing c-axis elongation of the YBCO lattice near the BZO 1D-APC/YBCO interface to enable a coherent interface via reducing the BZO/YBCO lattice mismatch from originally 7.7% to 1.4%, leading to significantly enhanced pinning efficiency of BZO 1D-APCs, especially at high magnetic fields. In this work, the ML scheme is applied to thick BZO/YBCO films with total thickness in the range from 150 nm to 750 nm. Remarkably, comparable $J_c(B)$ was observed in these ML samples while at lower temperature and higher fields, the thicker BZO/YBCO ML films outperform their thinner counterparts in both higher value and less anisotropy of $J_c(B)$. At 750 nm thickness, $J_c(65\text{K}, 9\text{T})$ is $>1.2 \text{ MA/cm}^2$ and $J_c(30\text{K}, 9\text{T})$ reaches up to 12 MA/cm^2 with a variation of $\sim 25\%$ over the entire angular range of B field orientations. This result illustrates the critical role of the BZO 1D-APC/YBCO interface in the pinning efficiency of BZO 1D-APCs.

Keywords (Index Terms)—Multilayer, YBCO nanocomposite film, artificial pinning center, vortex pinning efficiency, interface engineering

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